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Applicants: James M. Holden, William A. McGahan, Richard A. Yarussi,
Pablo I. Rovira, and Roger R. Lowe-Web
Assignee: Nanometrics Incorporated
Title: Apparatus And Method For The Measurement Of Diffracting Structures
Serial No.: 09/670,000 Filing Date: September 25, 2000
Examiner: Unknown Group Art Unit: Unknown
Docket No.: M-9455 US

San Jose, California
April 2, 2001

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97(b)

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the documents listed on the accompanying PTO Form-1449 are called to the attention of the Examiner for the above patent application. In particular, Applicants call U.S. 5,963,329 by Conrad et al. to the Examiner's attention. Copies of these documents are enclosed.

Citation of these documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on April 2, 2001.

Michael J. Halbert 4-2-01
Attorney for Applicants Date of Signature

Respectfully submitted,

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